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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2400
Number of Logic Elements/Cells	10800
Total RAM Bits	81920
Number of I/O	166
Number of Gates	468252
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP Exposed Pad
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv400-4hq240c

Virtex Device/Package Combinations and Maximum I/O

Table 3: Virtex Family Maximum User I/O by Device/Package (Excluding Dedicated Clock Pins)

Package	XCV50	XCV100	XCV150	XCV200	XCV300	XCV400	XCV600	XCV800	XCV1000
CS144	94	94							
TQ144	98	98							
PQ240	166	166	166	166	166				
HQ240						166	166	166	
BG256	180	180	180	180					
BG352			260	260	260				
BG432					316	316	316	316	
BG560						404	404	404	404
FG256	176	176	176	176					
FG456			260	284	312				
FG676						404	444	444	
FG680							512	512	512

Virtex Ordering Information

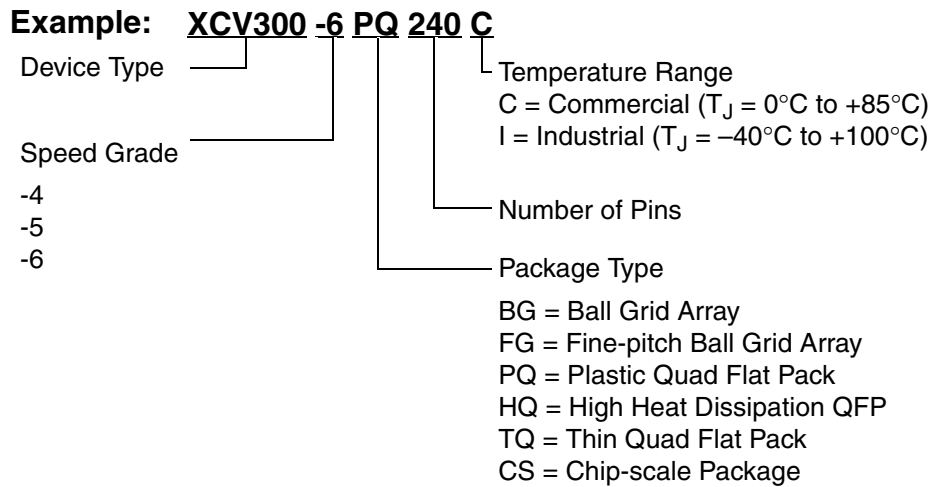


Figure 1: Virtex Ordering Information

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed..." statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul style="list-style-type: none"> Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	<ul style="list-style-type: none"> Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	<ul style="list-style-type: none"> Revised minimums for Global Clock Set-Up and Hold for LVTTTL Standard, with DLL. Converted file to modularized format. See Virtex Data Sheet section.
03/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
Pinout Tables (Module 4)

Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

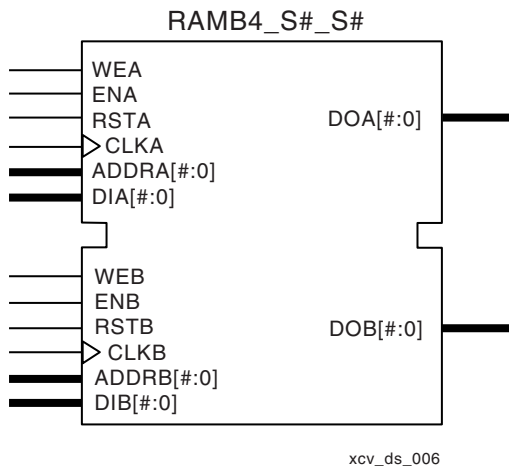


Figure 6: Dual-Port Block SelectRAM

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: Block SelectRAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

Programmable Routing Matrix

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

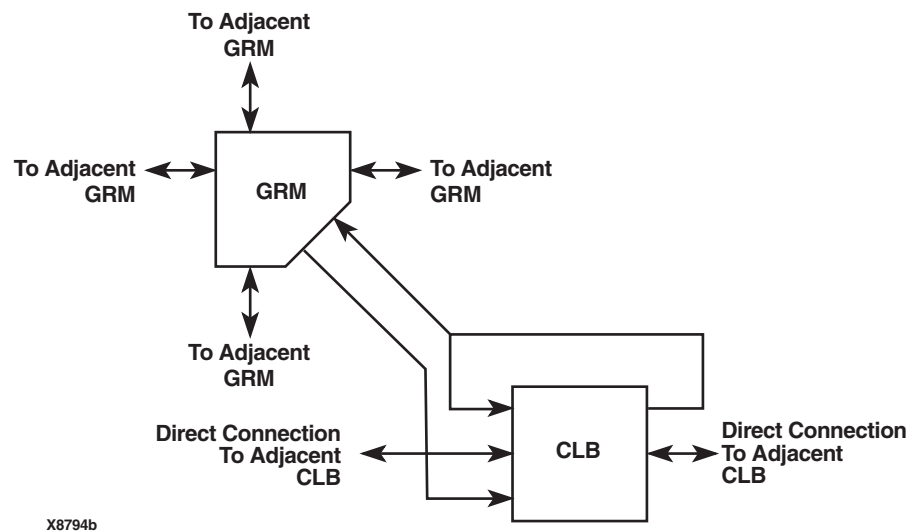


Figure 7: Virtex Local Routing

Local Routing

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM

- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in **Table 5**.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decoded by the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contribute all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in **Figure 11**.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

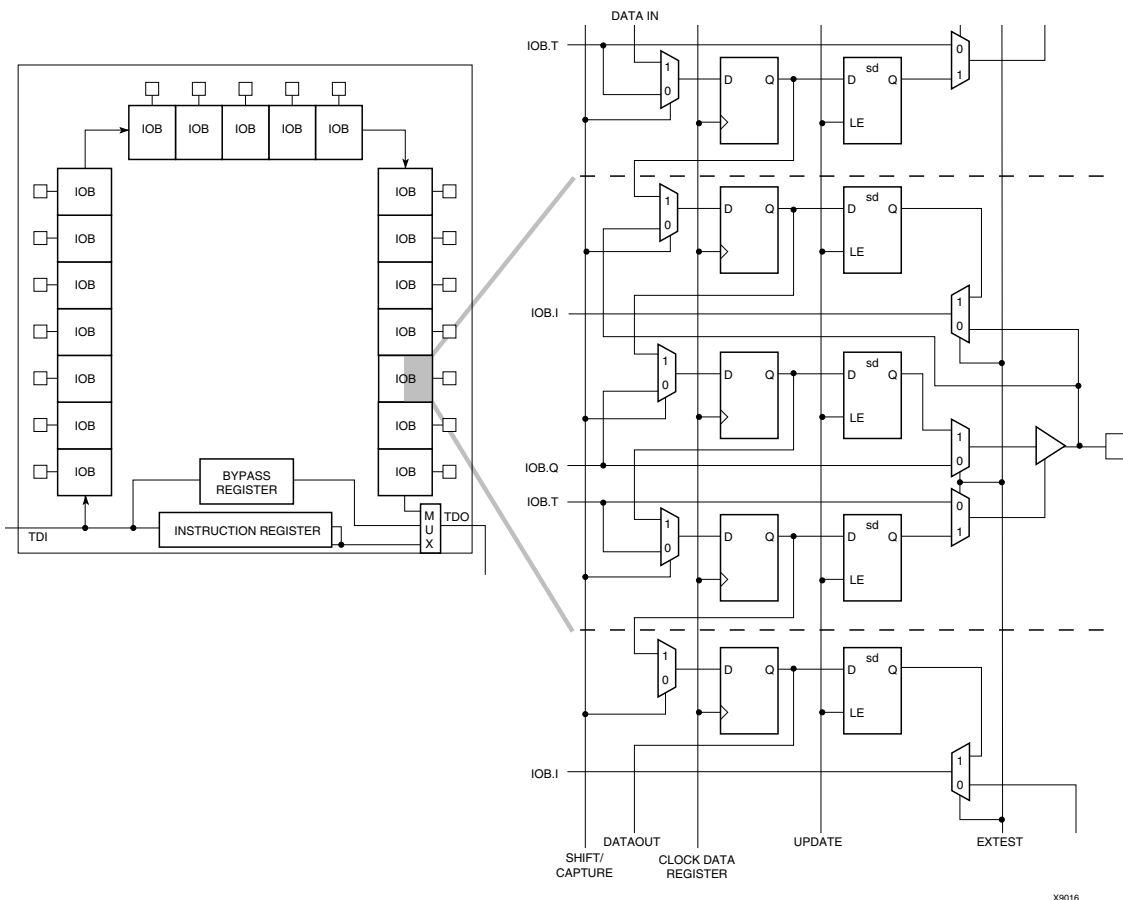


Figure 10: Virtex Series Boundary Scan Logic

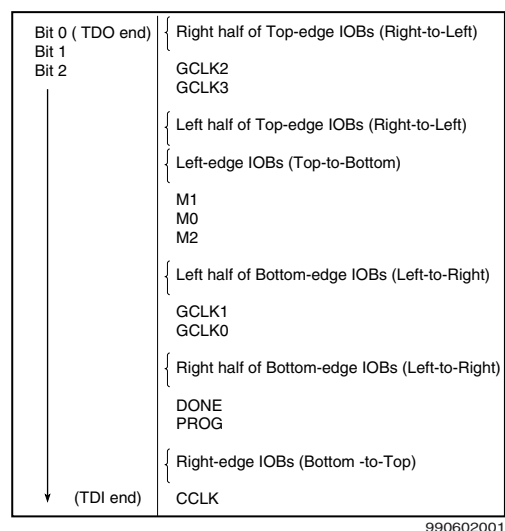


Figure 11: Boundary Scan Bit Sequence

Table 5: Boundary Scan Instructions

Boundary-Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE/PRELOAD	00001	Enables boundary-scan SAMPLE/PRELOAD operation
USER 1	00010	Access user-defined register 1
USER 2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables boundary-scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:ffa:aaaa:aaaa:cccc:cccc:ccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USER-CODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: IDCODEs Assigned to Virtex FPGAs

FPGA	IDCODE
XCV50	v0610093h
XCV100	v0614093h
XCV150	v0618093h
XCV200	v061C093h
XCV300	v0620093h
XCV400	v0628093h
XCV600	v0630093h
XCV800	v0638093h
XCV1000	v0640093h

Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

Development System

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-

ers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The “soft macro” portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical

design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRACE® static timing analyzer.

For in-circuit debugging, the development system includes a download and readback cable. This cable connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can single-step the logic, readback the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.

Configuration

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- $\overline{\text{PROGRAM}}$ pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a V_{CCO} of 3.3 V to permit LVTTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

Table 7: Configuration Codes

Configuration Mode	M2	M1	M0	CCLK Direction	Data Width	Serial D _{out}	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:

<http://www.xilinx.com/bvdocs/publications/ds026.pdf>.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

Configuration Modes

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

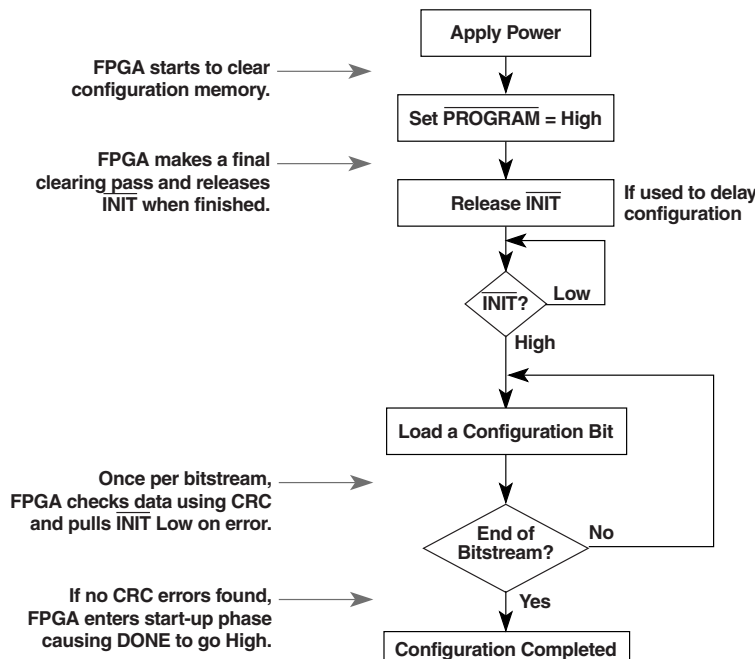
Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.



ds003_154_111799

Figure 15: Serial Configuration Flowchart

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained to permit high-speed 8-bit readback.

Retention of the SelectMAP port is selectable on a design-by-design basis when the bitstream is generated. If retention is selected, PROHIBIT constraints are required to prevent the SelectMAP-port pins from being used as user I/O.

Multiple Virtex FPGAs can be configured using the SelectMAP mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, WRITE, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the CS pin of each device in turn and writing the appropriate data. see Table 9 for SelectMAP Write Timing Characteristics.

Table 9: SelectMAP Write Timing Characteristics

	Description		Symbol		Units
CCLK	D ₀₋₇ Setup/Hold	1/2	T _{SMDCC} /T _{SMCCD}	5.0 / 1.7	ns, min
	$\overline{\text{CS}}$ Setup/Hold	3/4	T _{SMCSCC} /T _{SMCCCS}	7.0 / 1.7	ns, min
	$\overline{\text{WRITE}}$ Setup/Hold	5/6	T _{SMCCW} /T _{SMWCC}	7.0 / 1.7	ns, min
	BUSY Propagation Delay	7	T _{SMCKBY}	12.0	ns, max
	Maximum Frequency		F _{CC}	66	MHz, max
	Maximum Frequency with no handshake		F _{CCNH}	50	MHz, max

Write

Write operations send packets of configuration data into the FPGA. The sequence of operations for a multi-cycle write operation is shown below. Note that a configuration packet can be split into many such sequences. The packet does not have to complete within one assertion of $\overline{\text{CS}}$, illustrated in Figure 16.

1. Assert $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as described below.
2. Drive data onto D[7:0]. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more than one $\overline{\text{CS}}$ should be asserted.

IOB Input Switching Characteristics Standard Adjustments

Description	Symbol	Standard ⁽¹⁾	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific data input delay adjustments	T _{ILVTTL}	LVTTL	0	0	0	0	ns
	T _{ILVCMOS2}	LVCMSO2	−0.02	−0.04	−0.04	−0.05	ns
	T _{IPCI33_3}	PCI, 33 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns
	T _{IPCI33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns
	T _{IPCI66_3}	PCI, 66 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns
	T _{IGTL}	GTL	0.10	0.20	0.23	0.26	ns
	T _{IGTLP}	GTL+	0.06	0.11	0.12	0.14	ns
	T _{IHSTL}	HSTL	0.02	0.03	0.03	0.04	ns
	T _{ISSTL2}	SSTL2	−0.04	−0.08	−0.09	−0.10	ns
	T _{ISSTL3}	SSTL3	−0.02	−0.04	−0.05	−0.06	ns
	T _{ICTT}	CTT	0.01	0.02	0.02	0.02	ns
	T _{IAGP}	AGP	−0.03	−0.06	−0.07	−0.08	ns

Notes:

1. Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see [Table 3](#).

IOB Output Switching Characteristics

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays with the values shown in [IOB Output Switching Characteristics Standard Adjustments, page 9](#).

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Propagation Delays						
O input to Pad	T _{IOOP}	1.2	2.9	3.2	3.5	ns, max
O input to Pad via transparent latch	T _{IOOLP}	1.4	3.4	3.7	4.0	ns, max
3-State Delays						
T input to Pad high-impedance ⁽¹⁾	T _{IOTHZ}	1.0	2.0	2.2	2.4	ns, max
T input to valid data on Pad	T _{IOTON}	1.4	3.1	3.3	3.7	ns, max
T input to Pad high-impedance via transparent latch ⁽¹⁾	T _{IOTLPHZ}	1.2	2.4	2.6	3.0	ns, max
T input to valid data on Pad via transparent latch	T _{IOTLPON}	1.6	3.5	3.8	4.2	ns, max
GTS to Pad high impedance ⁽¹⁾	T _{GTS}	2.5	4.9	5.5	6.3	ns, max
Sequential Delays						
Clock CLK						
Minimum Pulse Width, High	T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{CL}	0.8	1.5	1.7	2.0	ns, min

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Clock CLK to Pad delay with OBUFT enabled (non-3-state)	T_{IOCKP}	1.0	2.9	3.2	3.5	ns, max
Clock CLK to Pad high-impedance (synchronous) ⁽¹⁾	T_{IOCKHZ}	1.1	2.3	2.5	2.9	ns, max
Clock CLK to valid data on Pad delay, plus enable delay for OBUFT	T_{IOCKON}	1.5	3.4	3.7	4.1	ns, max
Setup and Hold Times before/after Clock CLK⁽²⁾		Setup Time / Hold Time				
O input	T_{IOOCK}/T_{IOCKO}	0.51 / 0	1.1 / 0	1.2 / 0	1.3 / 0	ns, min
OCE input	$T_{IOOCECK}/T_{IOCKOCE}$	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR input (OFF)	$T_{IOSRCKO}/T_{IOCKOSR}$	0.52 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min
3-State Setup Times, T input	T_{IOTCK}/T_{IOCKT}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
3-State Setup Times, TCE input	$T_{IOTCECK}/T_{IOCKTCE}$	0.41 / 0	0.9 / 0	0.9 / 0	1.1 / 0	ns, min
3-State Setup Times, SR input (TFF)	$T_{IOSRCKT}/T_{IOCKTSR}$	0.49 / 0	1.0 / 0	1.1 / 0	1.3 / 0	ns, min
Set/Reset Delays						
SR input to Pad (asynchronous)	T_{IOSRP}	1.6	3.8	4.1	4.6	ns, max
SR input to Pad high-impedance (asynchronous) ⁽¹⁾	T_{IOSRHZ}	1.6	3.1	3.4	3.9	ns, max
SR input to valid data on Pad (asynchronous)	T_{IOSRON}	2.0	4.2	4.6	5.1	ns, max
GSR to Pad	T_{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max

Notes:

1. 3-state turn-off delays should not be adjusted.
2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Clock Distribution Guidelines

Description	Device	Symbol	Speed Grade			Units
			-6	-5	-4	
Global Clock Skew ⁽¹⁾						
Global Clock Skew between IOB Flip-flops	XCV50	T _{GSKEWIOB}	0.10	0.12	0.14	ns, max
	XCV100		0.12	0.13	0.15	ns, max
	XCV150		0.12	0.13	0.15	ns, max
	XCV200		0.13	0.14	0.16	ns, max
	XCV300		0.14	0.16	0.18	ns, max
	XCV400		0.13	0.13	0.14	ns, max
	XCV600		0.14	0.15	0.17	ns, max
	XCV800		0.16	0.17	0.20	ns, max
	XCV1000		0.20	0.23	0.25	ns, max

Notes:

- These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.

Clock Distribution Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
GCLK IOB and Buffer						
Global Clock PAD to output.	T _{GPIO}	0.33	0.7	0.8	0.9	ns, max
Global Clock Buffer I input to O output	T _{GIO}	0.34	0.7	0.8	0.9	ns, max

Block RAM Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Sequential Delays						
Clock CLK to DOUT output	T _{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
ADDR inputs	T _{BACK} /T _{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T _{BDCK} /T _{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T _{BECK} /T _{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T _{BRCK} /T _{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T _{BWCK} /T _{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T _{BCCS}		3.0	3.5	4.0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

TBUF Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
IN input to OUT output	T _{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T _{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T _{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

Description	Symbol	Speed Grade			Units
		-6	-5	-4	
TMS and TDI Setup times before TCK	T_{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T_{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T_{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F_{TCK}	33	33	33	MHz, max

Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>with</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Output Delay Adjustments.	T _{ICKOFDLL}	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).
3. DLL output jitter is already included in the timing calculation.

Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>without</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V _{REF} such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T _{ICKOF}	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V_{REF} Bank 7 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	G3, H1	N/A	N/A	N/A
	XCV100/150	... + D1	D26, G26, L26	N/A	N/A
	XCV200/300	... + B2	... + E24	F28, F31, J30, N30	N/A
	XCV400	N/A	N/A	... + R31	E31, G31, K31, P31, T31
	XCV600	N/A	N/A	... + J28	... + H32
	XCV800	N/A	N/A	... + M28	... + L33
	XCV1000	N/A	N/A	N/A	... + D31
GND	All	C3, C18, D4, D5, D9, D10, D11, D12, D16, D17, E4, E17, J4, J17, K4, K17, L4, L17, M4, M17, T4, T17, U4, U5, U9, U10, U11, U12, U16, U17, V3, V18	A1, A2, A5, A8, A14, A19, A22, A25, A26, B1, B26, E1, E26, H1, H26, N1, P26, W1, W26, AB1, AB26, AE1, AE26, AF1, AF2, AF5, AF8, AF13, AF19, AF22, AF25, AF26	A2, A3, A7, A9, A14, A18, A23, A25, A29, A30, B1, B2, B30, B31, C1, C31, D16, G1, G31, J1, J31, P1, P31, T4, T28, V1, V31, AC1, AC31, AE1, AE31, AH16, AJ1, AJ31, AK1, AK2, AK30, AK31, AL2, AL3, AL7, AL9, AL14, AL18, AL23, AL25, AL29, AL30	A1, A7, A12, A14, A18, A20, A24, A29, A32, A33, B1, B6, B9, B15, B23, B27, B31, C2, E1, F32, G2, G33, J32, K1, L2, M33, P1, P33, R32, T1, V33, W2, Y1, Y33, AB1, AC32, AD33, AE2, AG1, AG32, AH2, AJ33, AL32, AM3, AM7, AM11, AM19, AM25, AM28, AM33, AN1, AN2, AN5, AN10, AN14, AN16, AN20, AN22, AN27, AN33
GND ⁽¹⁾	All	J9, J10, J11, J12, K9, K10, K11, K12, L9, L10, L11, L12, M9, M10, M11, M12	N/A	N/A	N/A
No Connect	All	N/A	N/A	N/A	C31, AC2, AK4, AL3

Notes:

1. 16 extra balls (grounded) at package center.

Pinout Diagrams

The following diagrams, **CS144 Pin Function Diagram**, page 17 through **FG680 Pin Function Diagram**, page 27, illustrate the locations of special-purpose pins on Virtex FPGAs. Table 5 lists the symbols used in these diagrams. The diagrams also show I/O-bank boundaries.

Table 5: Pinout Diagram Symbols

Symbol	Pin Function
*	General I/O
*	Device-dependent general I/O, n/c on smaller devices
V	V _{CCINT}
v	Device-dependent V _{CCINT} , n/c on smaller devices
O	V _{CCO}
R	V _{REF}
r	Device-dependent V _{REF} , remains I/O on smaller devices
G	Ground
Ø, 1, 2, 3	Global Clocks

Table 5: Pinout Diagram Symbols (Continued)

Symbol	Pin Function
⑩, ①, ②	M0, M1, M2
⑩, ①, ②, ③, ④, ⑤, ⑥, ⑦	D0/DIN, D1, D2, D3, D4, D5, D6, D7
B	DOUT/BUSY
D	DONE
P	PROGRAM
I	INIT
K	CCLK
W	WRITE
S	CS
T	Boundary-scan Test Access Port
+	Temperature diode, anode
–	Temperature diode, cathode
n	No connect

CS144 Pin Function Diagram

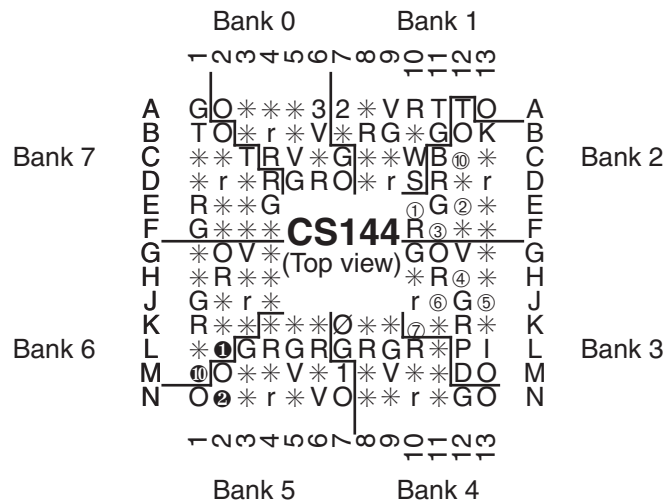
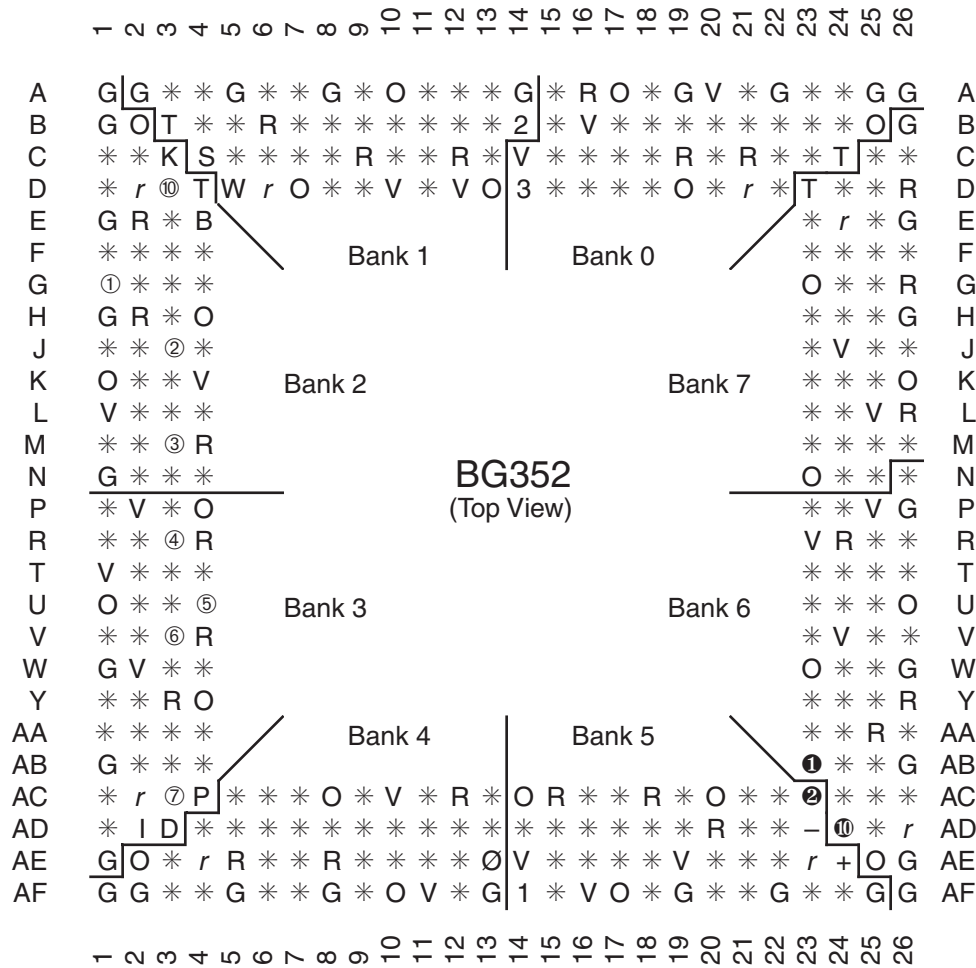


Figure 1: CS144 Pin Function Diagram

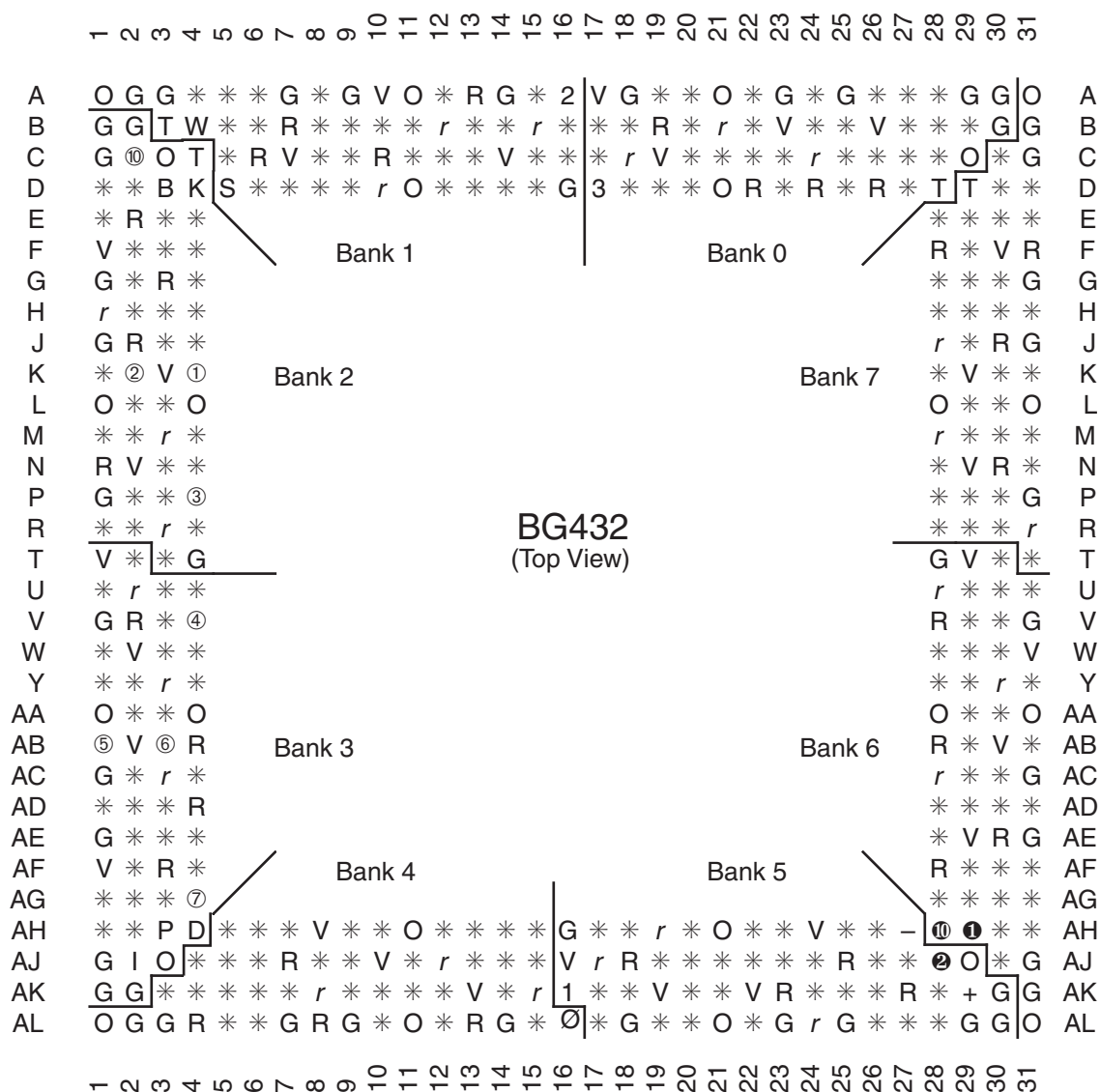
BG352 Pin Function Diagram



DS003_19_100600

Figure 5: BG352 Pin Function Diagram

BG432 Pin Function Diagram



DS003_21_100300

Figure 6: BG432 Pin Function Diagram

FG676 Pin Function Diagram

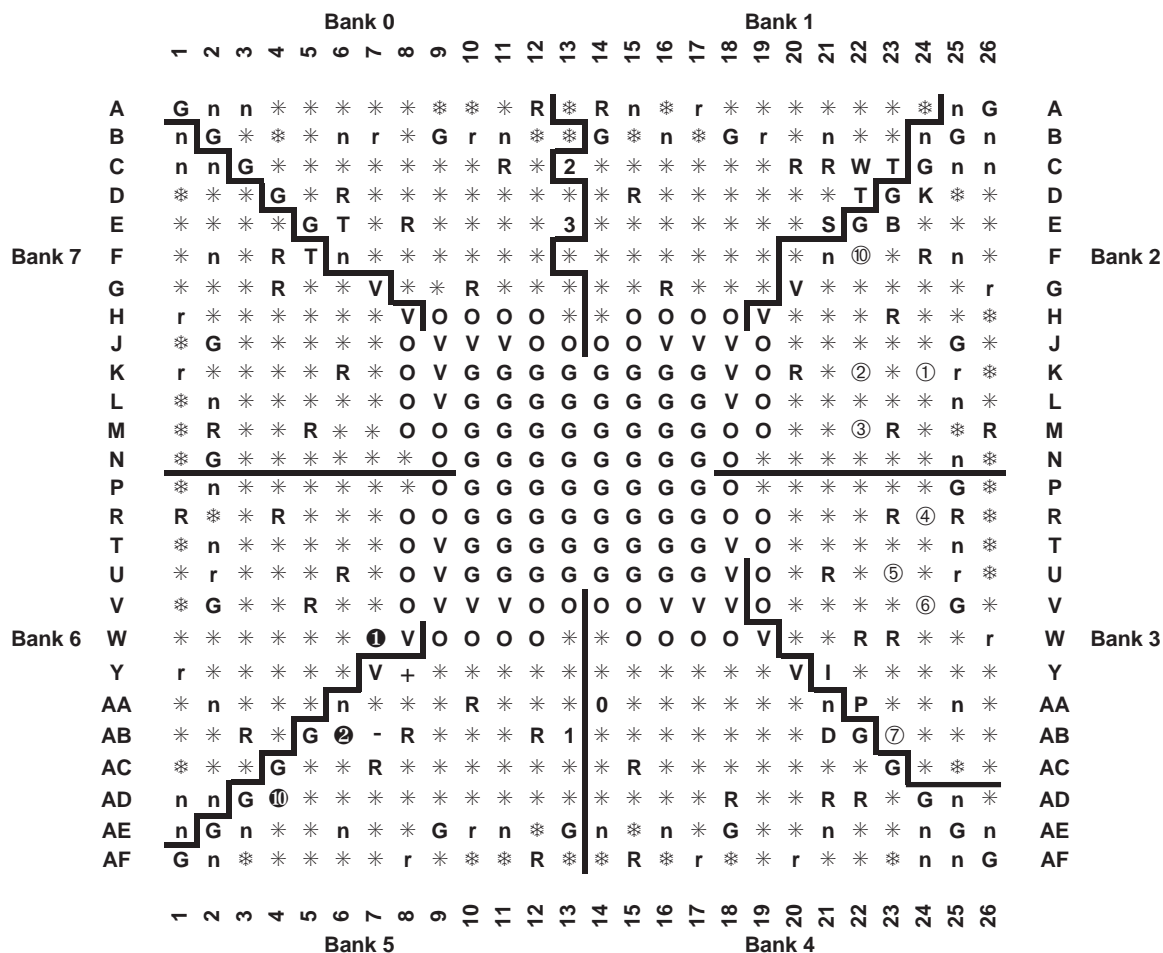


Figure 10: FG676 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.